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Ru oxidation states in fluorinated Ca₂RuO₄ thin films revealed by X-ray photoemission spectroscopy

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1 Introduction

Layered ruthenium oxyfluorides have various crystal structures and Ru oxidation states and exhibit unique physical properties. While various layered ruthenates have reportedly been topochemically fluorinated with Sr as A sites, the fluorination of layered ruthenates containing smaller Ca ions has not been investigated. In this study, we fabricated phase-pure and single-crystalline thin films of fluorinated Ca2RuO4 on LaSrAlO4 (001) substrates via topochemical fluorination of the Ca2RuO4 precursor using polyvinylidene fluoride and characterized the films. We found that the obtained fluorinated thin films had a chemical composition of Ca2RuO2.5F2 and a Ru3+ state, as determined by energy-dispersive X-ray (EDS) and X-ray photoemission spectroscopy spectroscopy (XPS).

2 Experiment

Layered perovskite Ca_2RuO_4 precursor films were grown on LaSrAlO₄ (001) substrates using the pulsed laser deposition and solid-phase epitaxy techniques. The Ca₂RuO₄ precursor films were subsequently fluorinated by heating with PVDF under Ar gas flow at 220 °C for 12 h.

The crystal structures of the films were characterized by X-ray diffraction analysis conducted using Cu- $K\alpha$ radiation. The chemical compositions were determined through EDS in conjunction with a scanning electron microscope. Ru 3p and Ca 2p XPS spectra were measured at 300 K using a VG-SCIENTASES-2002 electron energy analyzer with an energy resolution of 300 meV at a photon energy of 1200 eV. The Fermi level of the samples was set as that of an *in situ* evaporated gold foil that was in electrical contact with the sample.

3 Results and Discussion

To investigate the valence of Ru, core-level XPS spectra of Ru 3p and Ca 2s for the Ca₂RuO₄ and fluorinated films were measured, as shown in Fig. 1. In the spectrum of the Ca₂RuO₄ film, the Ru spinorbit split doublet— $3p_{1/2}$ and $3p_{3/2}$ —and the Ca 2s peak were clearly observed at binding energies (E_b) of 486.3, 464.2, and 438.2 eV, respectively. Upon fluorination, the Ru 3p peaks shifted to a 0.5 eV lower binding energy, suggesting that the valence of Ru in the fluorinated film is 3+, which is consistent with the chemical composition determined by EDS. This XPS result is in contrast to the fluorination of Sr₂Ru⁴⁺O₄ to Sr₂Ru⁴⁺O₃F₂, in which no peak shift of Ru 3p was observed [1]. It is speculated that the larger lattice distortion in Ca_2RuO_4 , which originates from the smaller ionic radius of Ca, leads to the easier release of oxygen from the RuO₆ octahedra. Considering the EDS and XPS (Fig. 1) results, we determined the chemical composition of the fluorinated thin film as Ca₂RuO_{2.5}F₂. In contrast to the Ru 3p peaks, the Ca 2s peak shifted to a 1.2 eV higher binding energy upon fluorination, which suggests a change in the bonding environment around Ca [1-3].

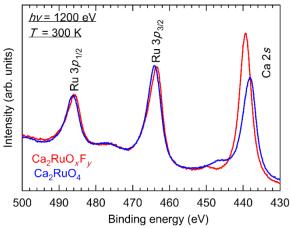


Fig. 1: Ru 3*p* and Ca 2*s* XPS spectra of the Ca₂RuO₄ precursor and the fluorinated films. The spectra were normalized by the peak height corresponding to Ru $3p_{3/2}$.

References

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